

Date: May 13, 2024

To whom it might concern,

We, Gantner Electronic GmbH, Bundesstraße 12, 6714 Nüziders, Austria, declare that our products GAT ECO.Lock 7102 NW F/ISO, GAT ECO.Lock 7102 NW F/ISO ICLS AND LM100:

FCC-ID: NC4-LM100

IC-ID: 11873A-LM100

PMN: XS4 ECO.Lock and GAT ECO.Lock

HVIN: GAT ECO.Lock 7102 NW/ISO, GAT ECO.Lock 7102 NW/ISO ICLS and LM100

The GAT ECO.Lock and XS4 ECO.Lock electronic locks are the ideal solution for the convenient locking of lockers in leisure facilities, universities, and company offices. GAT ECO.Lock is the product marketing name of electronic models GAT ECO.Lock 7102 NW F/ISO and GAT ECO.Lock 7102 NW F/ISO ICLS. XS4 ECO.Lock is the product marketing name of electronic model LM100

The electronic models GAT ECO.Lock 7102 NW F/ISO, GAT ECO.Lock 7102 NW F/ISO ICLS and LM100 have one circuit, the control circuit.

The control circuit references that are part of each electronic model are shown in the following table.

ELECTRONIC MODEL	HW VERSION	CONTROL CIRCUIT
GAT ECO.Lock 7102 NW F/ISO	1.2	GAT-ECO.Lock7002 V1.2 (2)
GAT ECO.Lock 7102 NW F/ISO ICLS	1.2	GAT-ECO.Lock7002 V1.2 (3)
LM100	1.2	GAT-ECO.Lock7002 V1.2 (4)

The difference between the 3 models is:

Component		GAT ECO.Lock 7102 NW F/ISO	GAT ECO.Lock 7102 NW F/ISO ICLS	LM100
C37	330 nF	X	X	
C40	10 pF	X	X	
C52	100 nF		X	
C57	100 nF			X
C58	100 nF			X
C59	10 nF	X	X	
IC5	Secure Element			X
IC10	Motor driver			X
IC11	HID's next generation single chip secure element		X	
R28	1k			X
R31	0R			X
R38	10k			X

R41	0R			X
R42	3k6			X
R43	3k6			X
R44	1k	X	X	
R65	2R7	X	X	
R70	100k	X	X	
R71	0R		X	
R72	10k		X	
R73	0R		X	
R74	330R		X	
R75	10k		X	
R76	330R		X	
R87	100k	X	X	
T9	Mosfet N+P transistor	X	X	
T12	Mosfet N+P transistor	X	X	

Consequently, to all previously explained, the approach adopted for the testing is the following:

- Partial RF (Radiated) testing for NFC for LM100, GAT ECO.Lock 7102 NW F/ISO and GAT ECO.Lock 7102 NW F/ISO ICLS to get worst case configuration.
- Full RF Testing for NFC Radio according to CFR Part 15.225, RSS-210 Issue 10/ANSI C63.10-2013 for the worst case found in Partial RF testing for NFC.
- Partial RF testing (radiated) for Bluetooth (1Mbps) Radio for LM100, GAT ECO.Lock 7102 NW F/ISO and GAT ECO.Lock 7102 NW F/ISO ICLS according to CFR Part 15.247, RSS-247 Issue 2.
- Full RF Testing for Bluetooth (1Mbps) Radio according to CFR Part 15.247, RSS-247 Issue 2 / ANSI C63.10-2013 for the worst case found in Partial RF testing for Bluetooth.
- EMC testing according to 47CFR Part 15B, ICES-003 Issue 7/ANSI C63.4-2014 to worst case configuration between LM100 and GAT ECO.Lock 7102 NW F/ISO.
- EMC testing according to 47CFR Part 15B, ICES-003 Issue 7/ANSI C63.4-2014 for GAT ECO.Lock 7102 NW F/ISO ICLS.
- Radiated Spurious Simultaneous Transmission Verification according to 47 CFR Part 2.947 (f) for the model with NFC worst case and Bluetooth worst case.

GANTNER Electronic GmbH | Bundesstr. 12 | A-6714 Nüziders

Sincerely,

A handwritten signature in black ink, appearing to read 'Seidlich', is positioned above a horizontal line.

By: Georg Seidlich
Title: COO / QM Officer
Company: Gantner Electronic GmbH
Telephone: +43 5552 33944
e-mail: georg.seidlich@gantner.com